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UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of: **YAMAGISHI, Yasuo, et al.**

Group Art Unit: **2829**

Serial No.: **10/621,445**

Examiner: **Jermele M. HOLLINGTON**

Filed: **July 18, 2003**

P.T.O. Confirmation No.: 1112

For: **PROBE CARD AND TESTING METHOD OF SEMICONDUCTOR CHIP,
CAPACITOR AND MANUFACTURING METHOD THEREOF**

AMENDMENT UNDER 37 CFR §1.116
- EXPEDITED RESPONSE -
GROUP ART UNIT 2829

MAIL STOP AF

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

June 5, 2006

Sir:

In response to the Final Office Action dated **April 18, 2006**, please amend the above-identified application as follows: